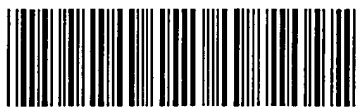


Search Notes 	Application/Control No. 10643672	Applicant(s)/Patent Under Reexamination RAY ET AL.
	Examiner Chawan, Sheela C	Art Unit 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	103,118,199,190,305	12/22/06	SCC
709	204,205	12/22/06	SCC
355	75	12/22/06	SCC
715	759,753	12/22/06	SCC
370	260	12/22/06	SCC
379	202.01	12/22/06	SCC
34	117	12/22/06	SCC
382	118, 199, 305	9/28/07	SCC
ABOVE SEARCH UP-DATE.		9/28/07	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
EAST, US-PGPUB,USPAT,EPO,JPO,DERWENT,IBM-TDB.	12/22/06	SCC
INVENTOR NAME SEARCH.	12/22/06	SCC
SEARCH EAST AND OTHER DATA BASE SEE ATTACHED SEARCH HISTORY.	9/28/07	SCC
382/103, 118, 199, 190, 305.CCLS. US-PATENT ONLY , SEE TEXT SEARCH.	9/28/07	SCC
709/204, 205.CCLS.	9/28/07	SCC
355/75.CCLS.	9/28/07	SCC
715/759, 753.CCLS.	9/28/07	SCC
370/260.CCLS.	9/28/07	SCC
379/202.01.CCLS.	9/28/07	SCC
34/117.CCLS.	9/28/07	SCC
INTERFERENCE SEARCH , SEE SEARCH HISTORY PRINT OUT.	9/28/07	SCC
SEARCH IEEE OR INSPEC DATA BASE.	9/28/07	SCC
ABOVE SEARCH UP-DATE.	9/28/07	SCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	118, 199, 305	9/28/07	SCC